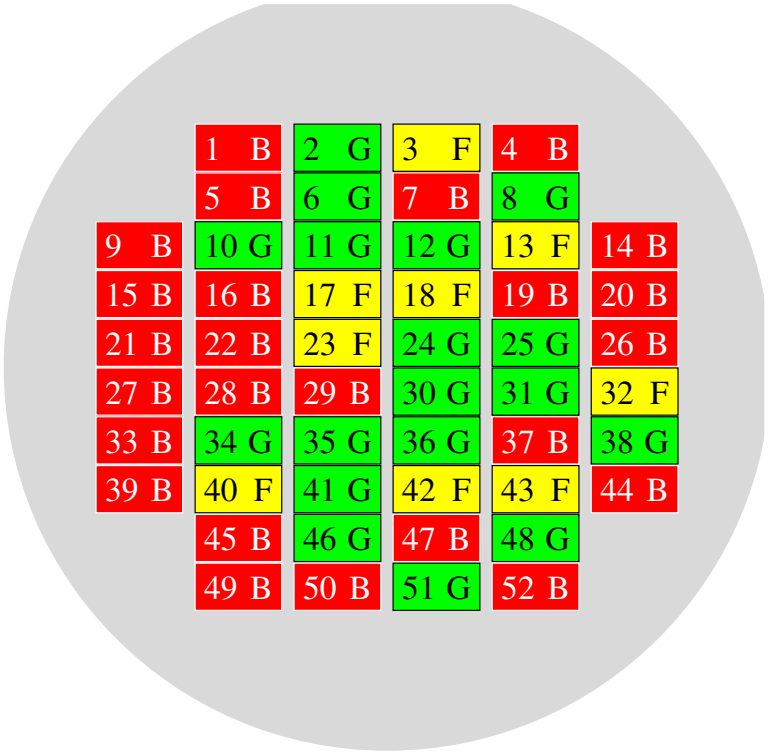
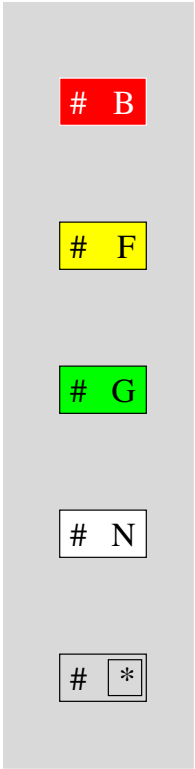
Die quality map for wafer 106 s/n: 21316-07-20

Date: 02/02/99





Bad die

Fair die

Good die

No info

Manually tagged